1 Failure rate

$$\lambda(t) = \frac{f(t)}{1 - F(t)}$$
$$R(t) = 1 - F(t) = e^{-\int_0^t \lambda(u) du}$$

2 TTT-transform

$$H_F^{-1}(v) = \int_0^{F^{-1}(v)} (1 - F(u)) du, \quad 0 \le v \le 1$$

The TTT-plot is given by the points $(i/n, T(x_{(i)})/T(x_{(n)}))$ where $T(x_{(i)})$ is the total time on test until time $x_{(i)}$.

3 Estimates

3.1 Estimates of constant failure rate

n parallel test sockets, r=number of failures, T total time on test.

$$\begin{split} \widehat{\lambda} &= \frac{r}{T} \text{ (ML-estimate, unbiased for Type I-censoring with replacement)} \\ \widehat{\lambda} &= \frac{r-1}{T} \text{ (unbiased for Typ II-censoring)} \end{split}$$

Confidence interval, (exact for Typ II-censoring, approximate for Typ I-censoring)

$$\left(\frac{\chi^2_{1-\alpha/2}(2r)}{2T}, \frac{\chi^2_{\alpha/2}(2r)}{2T}\right)$$

3.2 Estimates of the survivor function

$$\begin{split} \widehat{R}(x) &= \prod_{\nu} \frac{n-\nu}{n-\nu+1} & \text{Kaplan-Meier} \\ \widehat{R}(x) &= e^{-\widehat{Z}(x)} & \text{där } \widehat{Z}(x) = \sum_{\nu} \frac{1}{n-\nu+1} & \text{Nelson} \end{split}$$

where the product and the sum are taken over ν such that $x_{(\nu)} \leq x$ are times of failures. $\widehat{Z}(x)$ is the Nelson estimate of the cumulative failure rate.

4 Measures of component importance

$$B(i) = \frac{\eta(i)}{2^{n-1}} \qquad \text{where } \eta(i) \text{ is the number of critical paths for } i$$

$$I^{B}(i) = \frac{\partial h(p)}{\partial p_{i}}$$

$$I^{CR}(i) = \frac{I^{B}(i)(1-p_{i})}{1-h(p)}$$

$$I^{VF}(i) = \frac{P(\bigcup_{j=1}^{m_{i}} E_{i})}{1-h(p)} \qquad \text{where } E_{j} \text{ is the event that all components in the } j \text{ : th minimal cut,}$$
in which component i is contained, fails
$$I^{IP}(i) = h(1_{i}, p) - h(p)$$

$$RAW(i) = \frac{1 - h(0_i, \mathbf{p})}{1 - h(\mathbf{p})}$$

$$RRW(i) = \frac{1 - h(\mathbf{p})}{1 - h(1_i, \mathbf{p})}$$

Risk Reduction Worth

5 Renewal theory

Let N(t) be the number of renewals up to time t in a renewal process and let T be the time between two renewals. Let m = E(T) and $\sigma^2 = V(T)$. For large t it holds that

$$\begin{split} E(N(t)) &\approx \frac{t}{m} \\ V(N(t)) &\approx \frac{\sigma^2 t}{m^3} \\ N(t) \text{ is approximately normally distributed} \end{split}$$

6 Associated variables

For a system with components with associated state variables it holds

$$\begin{split} \prod_{j=1}^k P(\kappa_j(\underline{\mathbf{X}}=1)) &\leq P(\Phi(\underline{\mathbf{X}})=1) \leq \coprod_{i=1}^s P(\rho_i(\underline{\mathbf{X}})=1) \\ \max_{1 \leq j \leq s} \prod_{i \in S_j} p_i &\leq P(\Phi(\underline{\mathbf{X}})=1) \leq \min_{1 \leq j \leq k} \coprod_{i \in K_j} p_i \end{split}$$